

# PE43665

## Product Specification

UltraCMOS® RF Digital Step Attenuator, 1 MHz–2 GHz



Peregrine  
Semiconductor

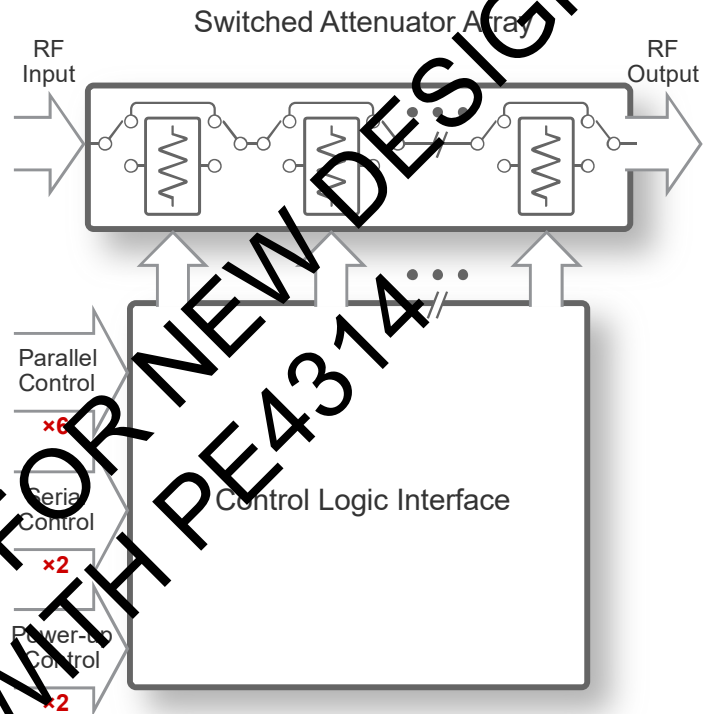
### Features

- 75Ω impedance
- Attenuation: 0.5 dB steps to 31.5 dB
- Low distortion for CATV and multi-carrier applications
- Flexible parallel and serial programming interfaces
- Unique power-up state selection
- Positive CMOS control logic
- High attenuation accuracy and linearity over temperature and frequency
- Very low power consumption
- Single-supply operation
- Packaged in a 20 lead 4x4 mm QFN

### Applications

- DOCSIS 3.1/3.0 customer premises equipment (CPE) and infrastructure
- Satellite CPE and infrastructure
- Fiber CPE and infrastructure

Figure 1 • Functional Schematic Diagram



### Product Description

The PE43665 is a 75-ohm, high-linearity, 6-bit RF Digital Step Attenuator (DSA) covering a 31.5 dB attenuation range in 0.5 dB steps. The PE43665 provides both a parallel (latched or direct mode) and serial CMOS control interface, operates on a single 3-volt supply and maintains high attenuation accuracy over frequency and temperature. It also has a unique control interface that allows the user to select an initial attenuation state at power-up. The PE43665 exhibits very low insertion loss and low power consumption. This functionality is delivered in a 4x4 mm QFN footprint.

The PE43665 is manufactured on Peregrine's UltraCMOS™ process, a patented variation of silicon-on-insulator (SOI) technology on a sapphire substrate, offering the performance of GaAs with the economy and integration of conventional CMOS.

## Absolute Maximum Ratings

Exceeding absolute maximum ratings listed in **Table 1** may cause permanent damage. Operation should be restricted to the limits in **Table 2**. Operation between operating range maximum and absolute maximum for extended periods may reduce reliability.

### ESD Precautions

When handling this UltraCMOS device, observe the same precautions as with any other ESD-sensitive devices.

Although this device contains circuitry to protect it from damage due to ESD, precautions should be taken to avoid exceeding the rating specified in **Table 1**.

### Latch-up Immunity

Unlike conventional CMOS devices, UltraCMOS devices are immune to latch-up.

**Table 1 • Absolute Maximum Ratings**

Symbol	Parameter/Conditions	Min	Max	Units
V <sub>DD</sub>	Power supply voltage	-0.3	4.0	V
V <sub>I</sub>	Voltage on any input	-0.3	V <sub>DD</sub> + 0.3	V
T <sub>ST</sub>	Storage temperature range	-65	150	°C
P <sub>IN</sub>	Input power (50Ω)		+30	dBm
V <sub>ESD</sub>	ESD voltage (Human Body Model) <sup>(1)</sup>		500	V

1. Human Body Model (HBM, MIL\_STD 883 Method 3015.7)

## Recommended Operating Conditions

**Table 2 • Recommended Operating Conditions for PE43665**

Parameter	Min	Typ	Max	Units
V <sub>DD</sub> Power Supply Voltage	2.7	3.0	3.3	V
I <sub>DD</sub> Power Supply Current			100	μA
Digital Input High	0.7xV <sub>DD</sub>			V
Digital Input Low			0.3xV <sub>DD</sub>	V
Digital Input Leakage			1	μA
Input Power			+24	dBm
Temperature range	-40		85	°C

**Table 3 • Electrical Specifications @ +25 °C,  $V_{DD} = 3.0V$ ,  $Z_o = 75 \Omega$**

Parameter	Test Conditions	Frequency	Min	Typ	Max	Units
Operation Frequency			1		2000	MHz
Insertion Loss <sup>2</sup>		1 MHz ≤ 1.2 GHz	-	1.4	1.8	dB
Attenuation Accuracy	Any bit or bit combination	1 MHz ≤ 1.2 GHz	-	-	±(0.15 + 4% of attenuation setting)	dB
1 dB Compression <sup>3,4</sup>		1 MHz ≤ 1.2 GHz	30	34		dBm
Input IP3 <sup>1,2,4</sup>	Two-tone inputs up to +18 dBm	1 MHz ≤ 1.2 GHz	-	52		dBm
Return Loss		1 MHz ≤ 1.2 GHz	10	13	-	dB
Switching Time	50% control to 0.5 dB of final value		-	-	1	µs

- Notes: 1. Device Linearity will begin to degrade below 1Mhz  
 2. Max input rating in Table 1 & Figures on Pages 6 to 8 for data across frequency.  
 3. Note Absolute Maximum in Table 1.  
 4. Measured in a 50 Ω system.

## Switching Frequency

The PE43665 has a maximum 25 kHz switching rate.

Switching frequency is defined to be the speed at which the DSA can be toggled across attenuation states.

Switching time is the time duration between the point the control signal reached 50% of the final value and the point the output signal reaches within 10% or 99% of its target value.

NOT RECOMMENDED FOR NEW DESIGNS  
REPLACE WITH PE4314

## Programming Options

### Parallel/Serial Selection

Either a parallel or serial interface can be used to control the PE43665. The P/S bit provides this selection, with P/S=LOW selecting the parallel interface and P/S=HIGH selecting the serial interface.

### Parallel Mode Interface

The parallel interface consists of five CMOS-compatible control lines that select the desired attenuation state, as shown in **Table 4**.

The parallel interface timing requirements are defined by **Figure 3** (Parallel Interface Timing Diagram), **Table 8** (Parallel Interface AC Characteristics), and switching speed (**Table 3**).

For latched parallel programming the Latch Enable (LE) should be held LOW while changing attenuation state control values, then pulse LE HIGH to LOW (per **Figure 3**) to latch new attenuation state into device.

For direct parallel programming, the Latch Enable (LE) line should be pulled HIGH. Changing attenuation state control values will change device state to new attenuation. Direct Mode is ideal for manual control of the device (using hardware, switches, or jumpers).

### Serial Interface

The serial interface is a 6-bit serial-in, parallel-out shift register buffered by a transparent latch. It is controlled by three CMOS-compatible signals: Data, Clock, and Latch Enable (LE). The Data and Clock inputs allow data to be serially entered into the shift register, a process that is independent of the state of the LE input.

The LE input controls the latch. When LE is HIGH, the latch is transparent and the contents of the serial shift register control the attenuator. When LE is brought LOW, data in the shift register is latched.

The shift register should be loaded while LE is held LOW to prevent the attenuator value from changing as data is entered. The LE input should then be toggled HIGH and brought LOW again, latching the new data. The timing for this operation is defined by **Figure 2** (Serial Interface Timing Diagram) and **Table 7** (AC Characteristics).

### Power-up Control Settings

The PE43665 always assumes a specifiable attenuation setting on power-up. This feature exists for both the Serial and Parallel modes of operation, and allows a known attenuation state to be established before an initial serial or parallel control word is provided.

When the attenuator powers up in Serial mode (P/S=1), the six control bits are set to whatever data is present on the six parallel data inputs (C0.5 to C16). This allows any one of the 64 attenuation settings to be specified as the power-up state.

When the attenuator powers up in Parallel mode (P/S=0) with LE=0, the control bits are automatically set to one of four possible values. These four values are selected by the two power-up control bits, PUP1 and PUP2, as shown in **Table 5** (Power-Up Truth Table, Parallel Mode).

**Table 4 • Truth Table**

P/S	C16	C8	C4	C2	C1	C0.5	Attenuation State
0	0	0	0	0	0	0	Reference Loss
0	0	0	0	0	0	1	0.5 dB
0	0	0	0	0	1	0	1 dB
0	0	0	0	1	0	0	2 dB
0	0	0	1	0	0	0	4 dB
0	0	1	0	0	0	0	8 dB
0	1	0	0	0	0	0	16 dB
0	1	1	1	1	1	1	31.5 dB

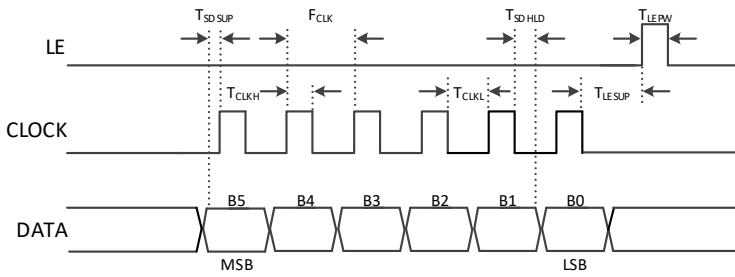
Note: Not all 64 possible combinations of C0.5-C16 are shown in table

**Table 5 • Parallel PUP Truth Table**

P/S	LE	PUP2	PUP1	Attenuation State
0	0	0	0	Reference Loss
0	0	1	0	8 dB
0	0	0	1	16 dB
0	0	1	1	31 dB
0	1	X	X	Defined by <b>C0.5-C16</b>

Note: Power up with LE=1 provides normal parallel operation with C0.5-C16, and PUP1 and PUP2 are not active.

**Figure 2 • Serial Interface Timing Diagram**



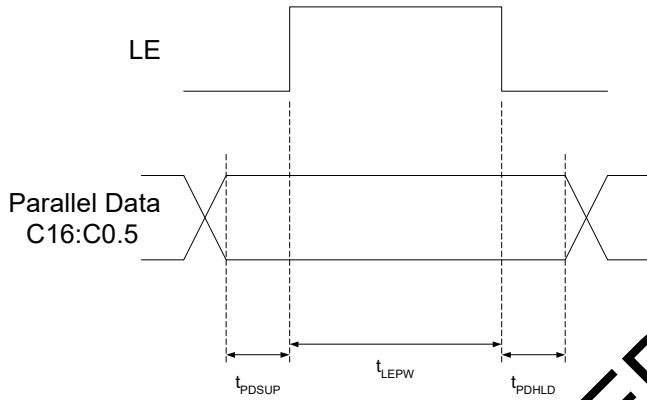
**Table 6 • 6-Bit Attenuator Serial Programming**

B5	B4	B3	B2	B1	B0
C16	C8	C4	C2	C1	C0

MSB (first in)

LSB (last in)

**Figure 3 • Parallel Interface Timing Diagram**



**Table 7 • Serial Interface AC Characteristics**

$V_{DD} = 3.0\text{ V}$ ,  $-40^\circ\text{ C} < T_A < 85^\circ\text{ C}$ , unless otherwise specified

Symbol	Parameter	Min	Max	Unit
$f_{CLK}$	Serial data clock frequency (Note 1)		10	MHz
$t_{CLKH}$	Serial clock HIGH time	30		ns
$t_{CLKL}$	Serial clock LOW time	30		ns
$t_{LESUP}$	LE set-up time after last clock falling edge	10		ns
$t_{LEPW}$	LE minimum pulse width	30		ns
$t_{SDSUP}$	Serial data set-up time before clock rising edge	10		ns
$t_{SDHLD}$	Serial data hold time after clock falling edge	10		ns

**Table 8 • Parallel Interface AC Characteristics**

$V_{DD} = 3.0\text{ V}$ ,  $-40^\circ\text{ C} < T_A < 85^\circ\text{ C}$ , unless otherwise specified

Symbol	Parameter	Min	Max	Unit
$t_{LEPW}$	LE minimum pulse width	10		ns
$t_{PDSUP}$	Data set-up time before rising edge of LE	10		ns
$t_{PDHLD}$	Data hold time after falling edge of LE	10		ns

NOTE:  $f_{CLK}$  is verified during the functional pattern test. Serial programming sections of the functional pattern are clocked at 10 MHz to verify  $f_{CLK}$  specification.

## Typical Performance Data

Figure 4–Figure 14 show the typical performance data at 25°C,  $V_{DD} = 3.0V$  unless otherwise specified.

Figure 4 • *Insertion Loss*

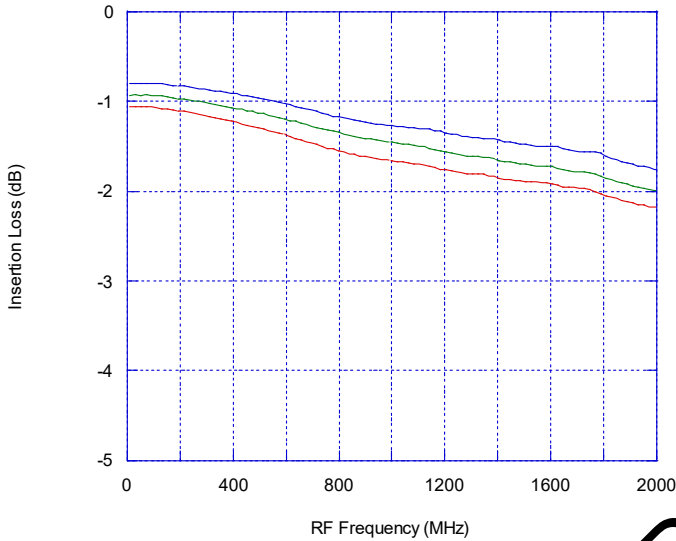


Figure 5 • *Attenuation at Major Steps*

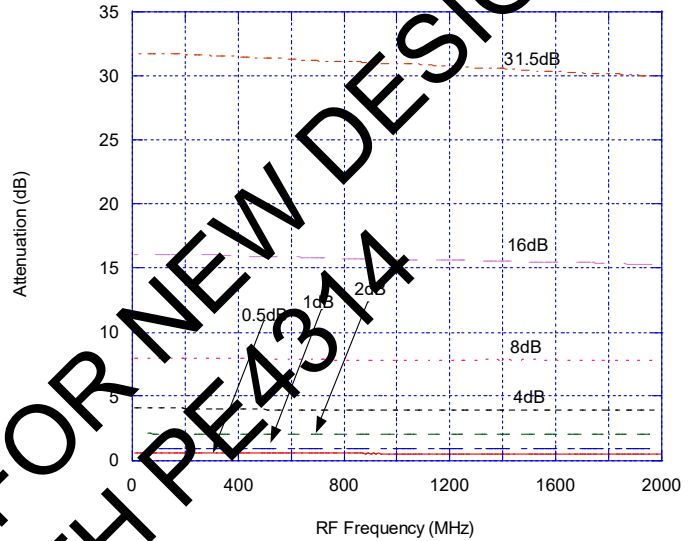


Figure 6 • *Input Return Loss at Major Attenuation Steps*

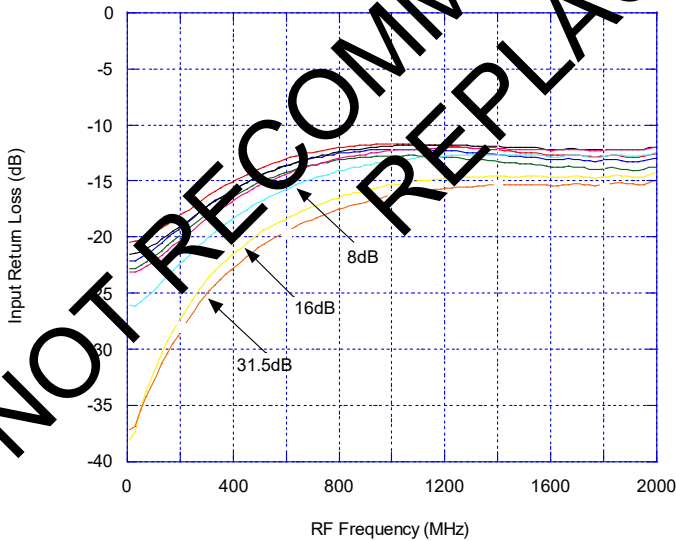


Figure 7 • *Output Return Loss at Major Attenuation Steps*

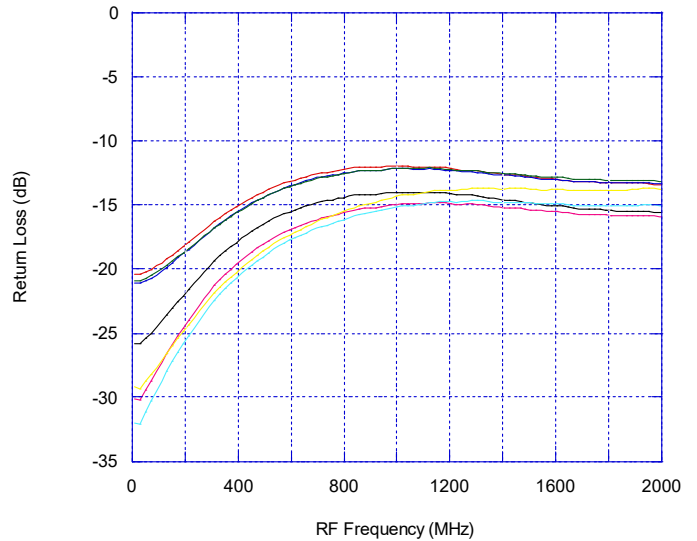


Figure 8 • Attenuation Error Vs. Frequency

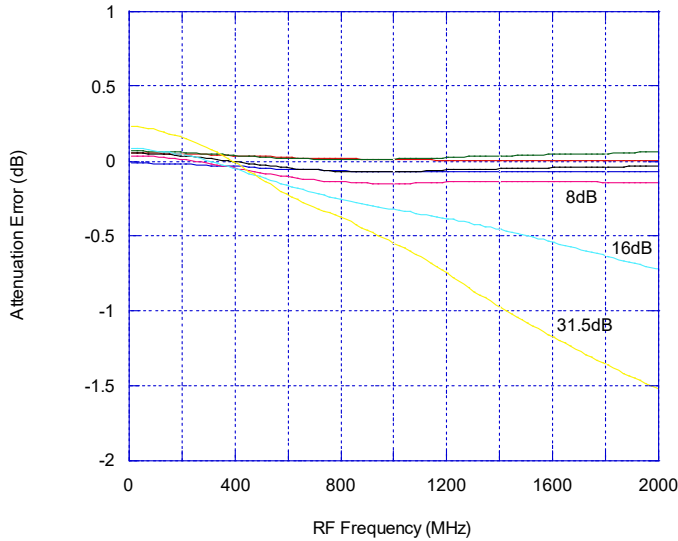


Figure 9 • Attenuation Error Vs. Attenuation Setting

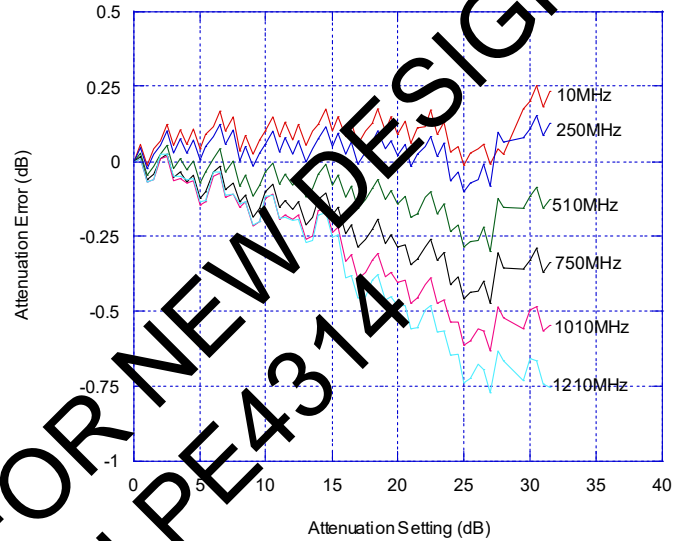


Figure 10 • Attenuation Error Vs. Attenuation Setting

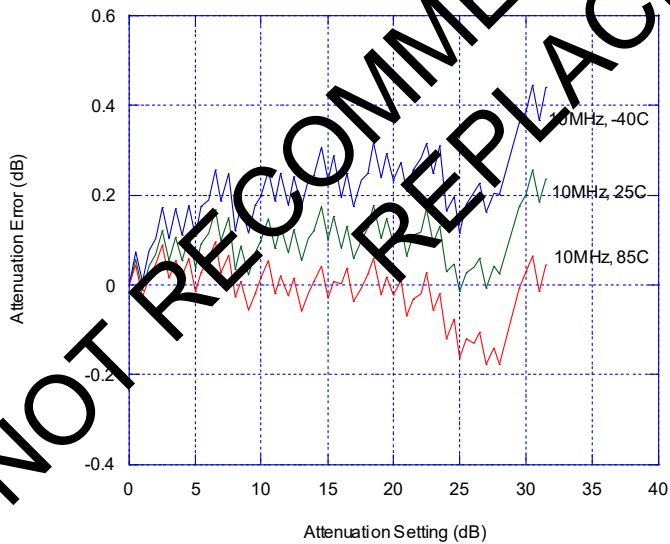
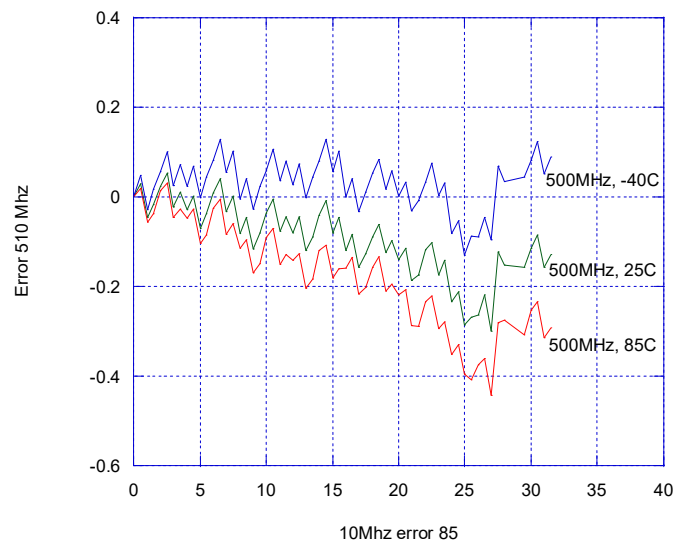


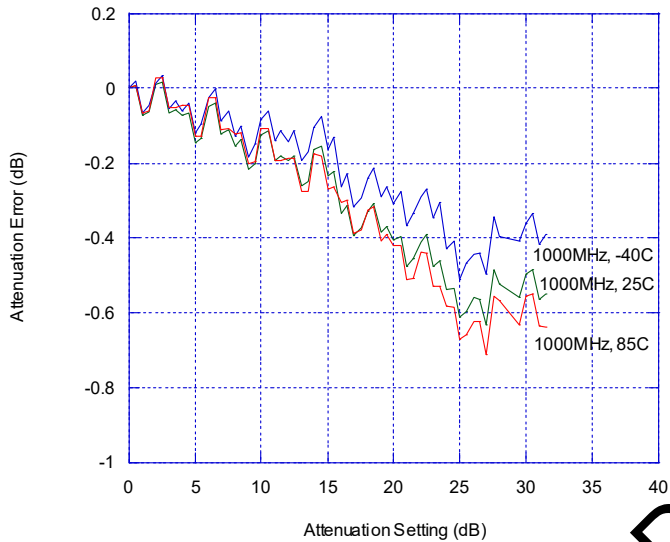
Figure 11 • Attenuation Error Vs. Attenuation Setting



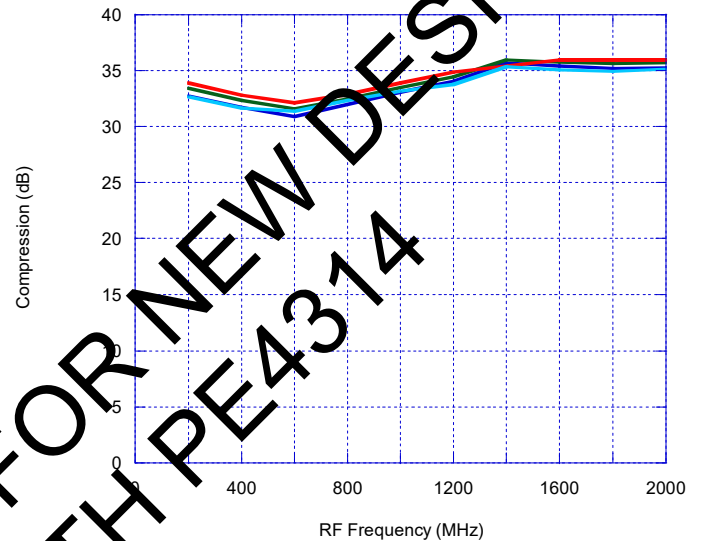
Note: Positive attenuation error indicates higher attenuation than target value

**Typical Performance Data @ 25°C,  $V_{DD} = 3.0 V$**

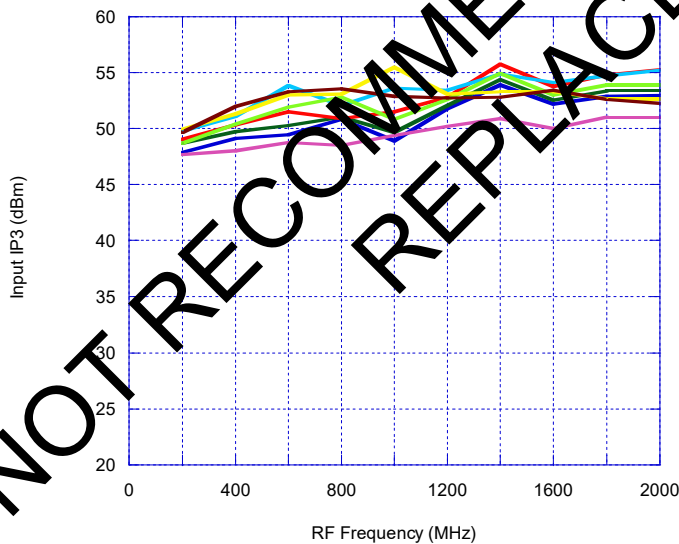
**Figure 12 • Attenuation Error Vs. Frequency**



**Figure 13 • Input 1 dB Compression**  
(Major attenuation states, 50 Ω System)



**Figure 14 • Input IP3 Vs. Frequency**  
(Major attenuation states, 50 Ω System)



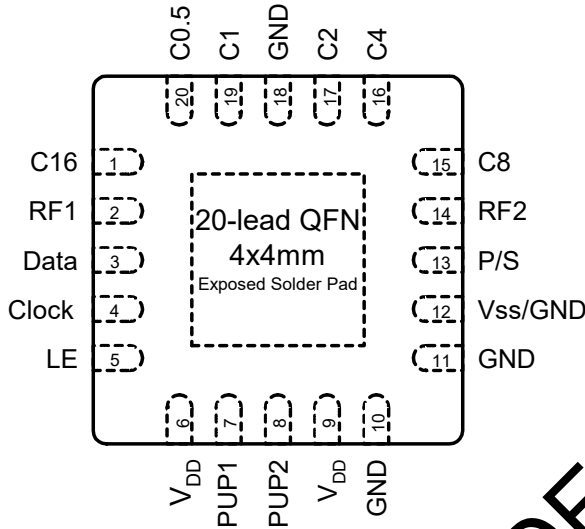
Note: Positive attenuation error indicates higher attenuation than target value

NOT RECOMMENDED FOR NEW DESIGNS  
REPLACE WITH PE4314

## Pin Information

This section provides pinout information for the PE43665. **Figure 18** shows the pin map of this device for the available package. **Table 9** provides a description for each pin.

**Figure 18 • Pin Configuration (Top View)**



**Table 9 • Pin Descriptions for PE43665**

Pin No.	Pin Name	Description
1	C16	Attenuation control bit, 16dB (Note 4).
2	RF1	RF port (Note 1).
3	Data	Serial interface data input (Note 4).
4	Clock	Serial interface clock input.
5	LE	Latch Enable input (Note 2).
6	V <sub>DD</sub>	Power supply pin.
7	PUP1	Power-up selection bit, MSB.
8	PUP2	Power-up selection bit, LSB.
9	V <sub>DD</sub>	Power supply pin.
10	GND	Ground connection.
11	GND	Ground connection.
12	V <sub>ss</sub> /GND	Negative supply voltage or GND connection (Note 3)
13	P/S	Parallel/Serial mode select.
14	RF2	RF port (Note 1).
15	C8	Attenuation control bit, 8 dB.
16	C4	Attenuation control bit, 4 dB.
17	C2	Attenuation control bit, 2 dB.
18	GND	Ground connection.
19	C1	Attenuation control bit, 1 dB.
20	C0.5	Attenuation control bit, 0.5 dB.
Paddle	GND	Ground for proper operation

Note 1: Both RF ports must be held at 0 V<sub>DC</sub> or DC blocked with an external series capacitor.

2: Latch Enable (LE) has an internal 100 kΩ resistor to V<sub>DD</sub>.

3: Connect pin 12 to GND to enable internal negative voltage generator. Connect pin 12 to V<sub>SS</sub> (-V<sub>DD</sub>) to bypass and disable internal negative voltage generator.

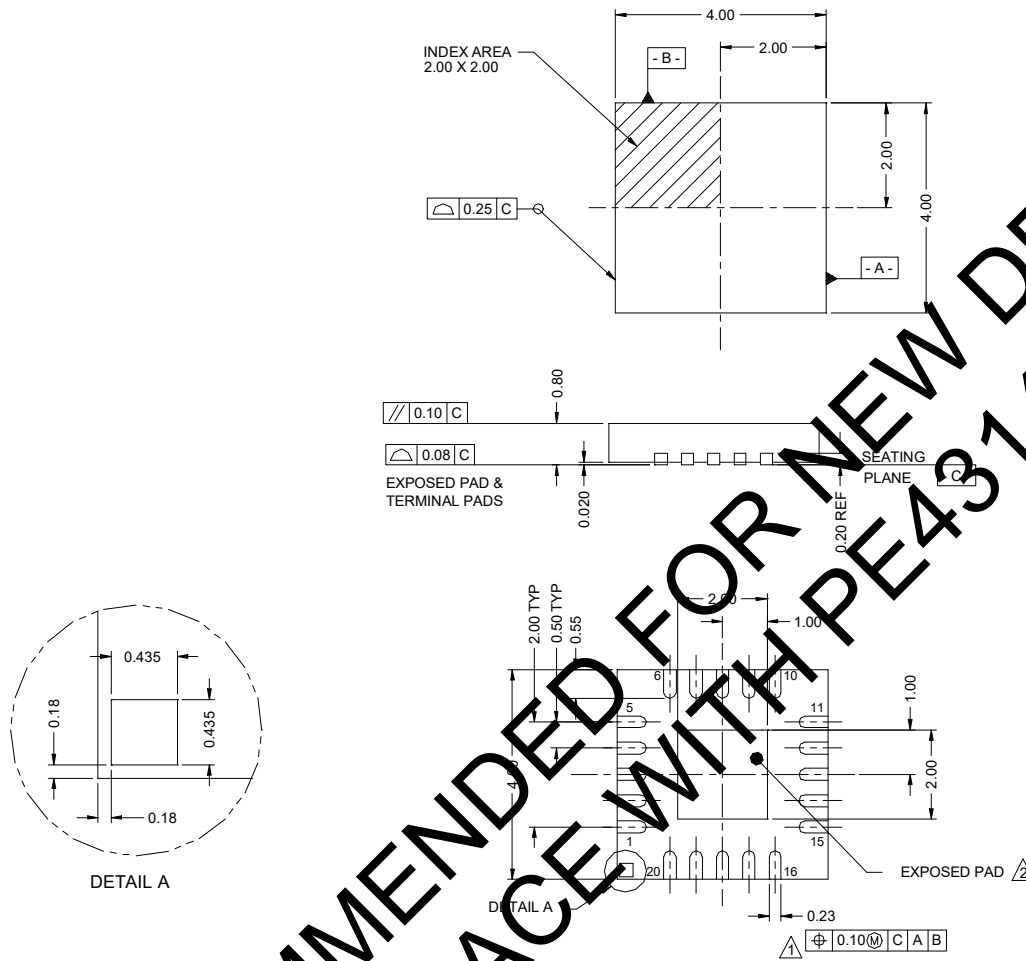
4: Place a 10 kΩ resistor in series, as close to pin as possible to avoid frequency resonance.

### Resistor on Pin 1 & 3

A 10 kΩ series resistor on the inputs to Pin 1 & 3 (see **Figure 18**) will eliminate package resonance between the RF input pin and the two digital inputs. Specified attenuation error versus frequency performance is dependent upon this condition.

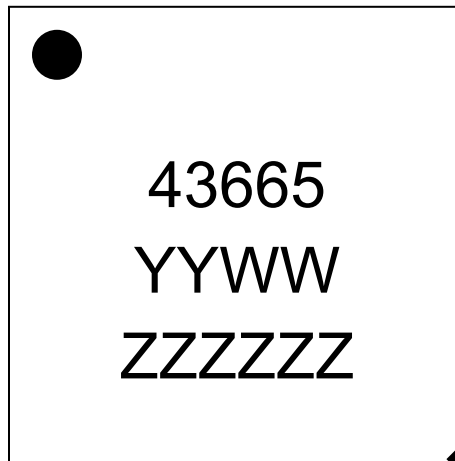
NOT RECOMMENDED FOR NEW DESIGN  
REPLACE WITH PE4374

Figure 19 • Package Drawing



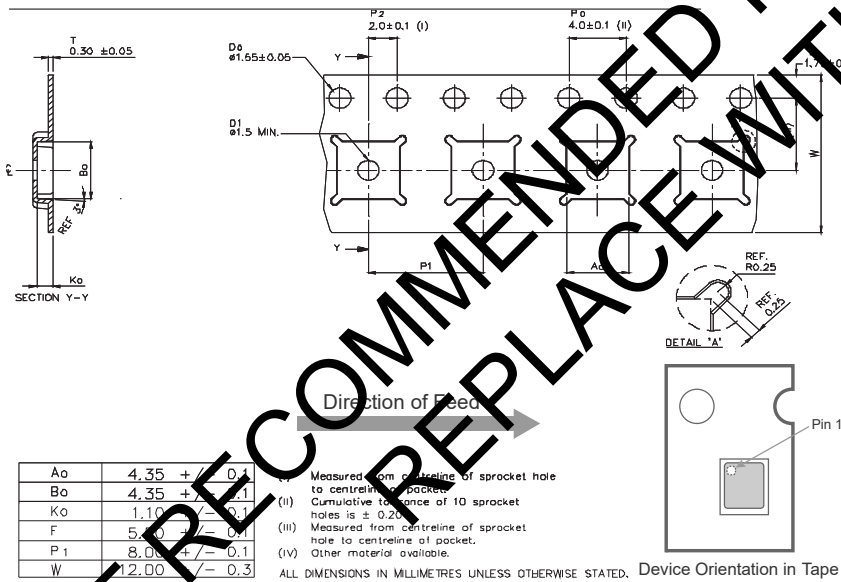
1. Dimension applies to metallized terminal and is measured between 0.25 and 0.30 from terminal tip.
2. Coplanarity applies to the exposed heat sink slug as well as the terminals.
3. Dimensions are in millimeters.

**Figure 20 • Marking Specifications**



YYWW = Date Code  
ZZZZZZ = Last six digits of lot number

**Figure 21 • Tape and Reel Drawing**



**Table 10 • Ordering Information**

Order Code	Description	Package	Shipping Method
PE43665A-Z	PE43665 Digital step attenuator	Green 20-lead 4x4mm QFN	3000 units / T&R
EK43665-01	PE43665 Evaluation kit	Evaluation Kit	1 / Box

## Document Categories

### Advance Information

The product is in a formative or design stage. The datasheet contains design target specifications for product development. Specifications and features may change in any manner without notice.

### Preliminary Specification

The datasheet contains preliminary data. Additional data may be added at a later date. pSemi reserves the right to change specifications at any time without notice in order to supply the best possible product.

### Product Specification

The datasheet contains final data. In the event pSemi decides to change the specifications, pSemi will notify customers of the intended changes by issuing a CNF (Customer Notification Form).

## Sales Contact

For additional information, contact Sales at [sales@psemi.com](mailto:sales@psemi.com).

## Disclaimers

The information in this document is believed to be reliable. However, pSemi assumes no liability for the use of this information. Use shall be entirely at the user's own risk. No patent rights or licenses to any circuits described in this document are implied or granted to any third party. pSemi's products are not designed or intended for use in devices or systems intended for surgical implant, or in other applications intended to support or sustain life, or in any application in which the failure of the pSemi product could create a situation in which personal injury or death might occur. pSemi assumes no liability for damages, including consequential or incidental damages, arising out of the use of its products in such applications.

## Patent Statement

pSemi products are protected under one or more of the following U.S. patents: [patents.psemi.com](http://patents.psemi.com)

## Copyright and Trademark

©2018, 2019 pSemi Corporation, a Murata company. All rights reserved. The Peregrine Semiconductor name, Peregrine Semiconductor logo and UltraCMOS are registered trademarks and the pSemi name, pSemi logo, HaRP and DuNE are trademarks of pSemi Corporation in the U.S. and other countries.